PATENT APPLICATION

Docket No.: 4591-333

Ae-Yong Chung, et al. September 25, 2003

Serial No.

10/672,994

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INFORMATION DISCLOSURE CITATION FORM PTO-1449 (Modified)

U.S. PATENT DOCUMENTS

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Exam Init	<u>Ref</u>	Document <u>Number</u>	Issue <u>Date</u>	<u>Name</u>	Sub <u>Class</u> <u>Class</u>					
FOREIGN PATENT DOCUMENTS										
Exam Init M M	<u>Ref</u>	Document Number 1020010084288 Aberral substitution 1020020013303 Aberral on 1020020023600 Aberral substitution	Feb. 20 02 Mar. 29, 02	Country Korea Korea Korea	Name Byeong-Gi JUNG Jong-Cheol KIM Byeong-Teak LEE, et al.					
Exam Init Me Me	<u>Ref</u>	English language abstract of Korean Publication No. 1020010084288 English language abstract of Korean Publication No. 1020020013303 English language abstract of Korean Publication No. 1020020023600								

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Ae-Yong Chung, et al.

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TEST APPARATUS HAVING MULTIPLE TEST SITES AT ONE HANDLER AND

ITS TEST METHOD

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FOREIGN PATENT DOCUMENTS

Exam <u>Init</u>	Ref	Document <u>Number</u>	Publication <u>Date</u>	Country	<u>Name</u>					
f/		2003-0057209 Abstract only	July 4, 2003 ^(*)	Korea						
	OTHER DOCUMENTS									
Exam Init Ref Author, Title, Date, Pertinent Pages, Etc.) English language abstract of Korean Publication No. 2003-0057209										
Examiner:										
Date Considered:										